



- To Advance Wafer Test Technology
- To Serve and Inform the Wafer Test Professional
- To Boldly Go Where No Workshop Has Gone Before

San Diego, CA, June 3 to 6, 2001



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WHAT IS SWTW - 2001?

- “THE” Conference for wafer test professionals
- Not a theoretical or academic conference
- Provides practical solutions to real problems
- Mixture of vendor and user presentations
- Open discussions and networking
- Informal and relaxed atmosphere



TECHNICAL PROGRAM

- Sunday, June 3, 2001
 - ◆ Introduction to Wafer Testing Tutorial
 - ◆ Plenary Session
 - Alex Oscilowski, (Kulicke & Soffa Test Division)
 - Fred Taber, (IBM Microelectronics)

- Monday, June 4, 2001
 - ◆ High Performance Probing
 - ◆ Vertical Probing
 - ◆ Probe Process Assessment I - Capability and Methods



TECHNICAL PROGRAM

- Tuesday, June 5, 2001
 - ◆ Prober and Probe Card Analyzer Performance
 - ◆ Memory Probing
 - ◆ Afternoon Social Activities
- Wednesday June 6, 2001
 - ◆ New Probe Technologies
 - ◆ Probe and Package Assembly
 - ◆ Awards Luncheon
 - ◆ SEMATECH Benchmarking Project Meeting



INFORMAL DISCUSSIONS

- Long breaks for discussion with “colleagues”
- Barefoot Bar cocktail party
- After dinner entertainment
- Recreational activities
 - ◆ Miniature Golf Tournament
 - ◆ SWTW - 2001 Amateur Sailing Regatta
 - ◆ Mission Bay Cruise



[Http://www.swtest.org](http://www.swtest.org)

- Central Online Repository
 - ◆ Past presentations
 - ◆ Committee members
 - ◆ Online registration
 - ◆ With more features to come.....
- Tremendous success !!
 - ◆ Over eight thousand visited our site last year
 - ◆ Thanks to our webmaster - Jerry Broz
 - ◆ Thanks to our Archivist - Rey Rincon



RECOGNITION & AWARDS

- Best Presentation
- Best Data Presented
- “Early Bird” Presentation Submitted
- Most “Inspirational” Presentation
- “Dead Ass Last” Presentation Submitted
- Other “Special Awards”



The BEST from SWTW - 2000

- **Rahima Mohammed and Jeannette Roberts, Intel**
“Thermal Characterization at Wafer Test:
Experiments and Numerical Modeling”
- **January Kister & Krzysztof Dabrowiecki, Probe Tech**
“Contact Mechanics for the Cantilever Probe Tip”
- **Tu Anh Tran, Lois Yong and Robert Radke, Motorola**
“Fine Pitch Probing, Wirebonding and Reliability
of Aluminum Capped Copper Bond Pads”



***“You go to San Diego and
have a lot of fun.....***

***.....all I get is this
crummy toy!”***



Test Technology Periodicals

International Test Conference

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Washington, DC 20036,
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Test Technology Technical Council

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Journal Of Electronic Testing

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Design And Test Of Computers,

10662 Los Vagueros Circle,
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EE - Evaluation Engineering

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Final Test Report

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IEEE Journals, Transactions, and Letters

Contact your local IEEE Chapter or Technical Library



NEW LOCATION NEXT YEAR

- **Long Beach, California**
- **Hyatt Regency Hotel**
- **Excellent Venue**
 - ◆ Close to LAX (30 minutes by Super Shuttle)
 - ◆ World class hotel and good rates
 - ◆ Harbor Sight Seeing Cruise
 - ◆ Aquarium of the Pacific
 - ◆ Other Southern California attractions



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